

**Notice of References Cited**

Application/Control No.

10/679,486

Applicant(s)/Patent Under  
Reexamination  
PIEN/MAKI ET AL.

Examiner

JASON K. GEE

Art Unit

2434

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*	B	US-2002/0174335	11-2002	Zhang et al.	713/168
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**NON-PATENT DOCUMENTS**

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